



Integrated Device Technology, Inc.  
2975 Stender Way, Santa Clara, CA - 95054

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: <b>F0206-07R1</b> DATE: 4/14/2003 Product Affected:      FIFO Products, see attached  Date Effective:      9/17/2002	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input checked="" type="checkbox"/> Date Code <input type="checkbox"/> Other
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Contact:      Dasharath Patel Title:      Quality Assurance Manager Phone #:      (408) 330-1488 Fax #:      (408) 330-1450 E-mail:      Dasharath.Patel@idt.com	Attachment:: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No  Samples:      Available on request
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**DESCRIPTION AND PURPOSE OF CHANGE:**

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>As a part of IDT's consolidation of wafer fab manufacturing operations, the attached devices are transferred from FAB-2 (Salinas, CA) to FAB-4 (Hillsboro, OR). There will be no change in manufacturing technology. The number "4" added to the stepping character will identify FAB-4 material. Please see attachment for details Starting 9/17/2002, customers will receive material manufactured either at FAB-2 or Fab 4</p> <p><u>Addendum:</u> This PCN is being re-issued to include qualification data, and to correct typographical errors in the attachment section of PCN # F0206-07 (original PCN document issued on 06/17/2002). The parts affected and effective date remain unchanged.</p>
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**RELIABILITY/QUALIFICATION SUMMARY:** Please see attachment for qualification summary

**CUSTOMER ACKNOWLEDGMENT OF RECEIPT:**  
 IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.  
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

**CUSTOMER COMMENTS:** \_\_\_\_\_

**IDT ACKNOWLEDGMENT OF RECEIPT:**

RECD. BY: \_\_\_\_\_      DATE: \_\_\_\_\_



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### ATTACHMENT - PCN #: F0206-07R1

**PCN Type:** Wafer Fabrication Site Change

**Data Sheet Change:** None

**Detail of Change:** Transfer of manufacturing site for attached devices, from fab-2 (Salinas, CA) to fab-4 (Hillsboro, OR).

#### Conversion schedule (Estimated)

Samples	Available on request
Production Shipments	9/17/2002



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## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### ATTACHMENT - PCN #: F0206-07R1

**Qualification Plan:** QFI-02-05

**Test Vehicle:** 7204

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

**Qualification Plan:** QFI-02-11

**Test Vehicle:** 72V04

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

**Characterization Data:** Characterization Data is available upon request.



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## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### ATTACHMENT - PCN #: F0206-07R1

**Qualification Plan:** QFI-02-09

**Test Vehicle:** 72211

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

**Qualification Plan:** QFI-02-10

**Test Vehicle:** 72V211

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

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## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### ATTACHMENT - PCN #: F0206-07R1

**Qualification Plan:** QFI-02-03

**Test Vehicle:** 72251

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

**Qualification Plan:** QFI-02-12

**Test Vehicle:** 72V251

Test Description/Condition	Test Methods	SS/# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

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## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### ATTACHMENT - PCN #: F0206-07R1

**Qualification Plan:** QFI-01-19R1

**Test Vehicle:** 72245

Test Description/Condition	Test Methods	SS /# Fails	Lot # 1 Test Results
Temperature Cycling (-65°C to +150°C, 500 cyc)	MIL-STD-883, Method 1010	45/0	45/0
Highly Accelerated Stress Test (HAST) (100 Hrs, @130°C/85%RH,Static Bias)	EIA/JESD22-A110	45/0	45/0
Auto Clave (SPP) (168Hrs, @ 2ATM, 121°C)	EIA/JESD22-A102	45/0	45/0
Life Test (+125°C, 1000 hrs)	MIL-STD-883, Method 1005	116/0	116/0
ESD Human Body Model (2000V)	MIL-STD-883, Method 3015	9/0	9/0
ESD Charge Device Model (500V)	JESD22-C101	6/0	6/0
Latch-Up Immunity (+I and Vstress, +- 100mA Trigger)	EIA/JESD 78	10/0	10/0

**Characterization Data:** Characterization Data is available upon request.



**ATTACHMENT - PCN #: F0206-07R1**

Device	Date Code Mark	
	Current	FAB4
IDT7203	Syyww	S4yyww
IDT7204	Syyww	S4yyww
IDT7283	Syyww	S4yyww
IDT7284	Syyww	S4yyww
IDT72200	Wyyww	W4yyww
IDT72201	Wyyww	W4yyww
IDT72210	Wyyww	W4yyww
IDT72211	Wyyww	W4yyww
IDT72220	Wyyww	W4yyww
IDT72230	Wyyww	W4yyww
IDT72240	Wyyww	W4yyww
IDT72251	Yyyww	Y4yyww
IDT72420	Wyyww	W4yyww
IDT72421	Wyyww	W4yyww
IDT72801	Wyyww	W4yyww
IDT72811	Wyyww	W4yyww
IDT72851	Yyyww	Y4yyww

Device	Date Code Mark	
	Current	FAB4
IDT72V03	Syyww	S4yyww
IDT72V04	Syyww	S4yyww
IDT72V83	Syyww	S4yyww
IDT72V84	Syyww	S4yyww
IDT72V201	Wyyww	W4yyww
IDT72V211	Wyyww	W4yyww
IDT72V251	Yyyww	Y4yyww
IDT72V801	Wyyww	W4yyww
IDT72V811	Wyyww	W4yyww
IDT72V851	Yyyww	Y4yyww

yyww: year/work week